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Attorney Docket Number 13621-43433

Application Number	10/625,769
Filing Date	07/23/2003
First Named Inventor	Brian G. Hoover
Art Unit	3738
Examiner Name	CHATTOPADHYAY, U.
Attorney Docket Number	13621-43433

U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ² Number ⁴ Kind Code ⁵ (if known)				

**Examiner
Signature**

M. Vargt

Date Considered

11/30/05

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		Number-Kind Code ² (if known)			
MDV	1	US- 4409258	10/11/1983	Feurer, et al.	
	2	US- 4655774	04/07/1987	Choyce	
	3	US- 5713957	02/03/1998	Steele, et al.	
	4	US- 6280469	08/28/2001	Terry, et al.	
	5	US- Pub 0018612	08/16/2001	Carson, et al.	
	6	US- 6361560	03/26/2002	Nigam, A.	
MDV	7	US- 6102946	03/26/2002	Nigam, A.	
		US-			

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Examiner Signature

M. Vagnet

Date Considered

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<i>First Named Inventor</i>	Brian G. Hoover
<i>Art Unit</i>	3738
<i>Examiner Name</i>	

Attorney Docket Number 13621-43433

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
WAPV	A	WOLF, STANLEY PH.D. AND TAUBER, RICHARD N. PH.D., "SILICON PROCESSING FOR THE VLSI ERA, Volume 1: Process Technology," Book, 1st ed., Lattice Press (Sunset Beach, California), p. 430-437, (February 8, 1986).	
	B	ZIEGLER, J.F.; BIERACK, J.P., LITTMARK, U., "THE STOPPING AND RANGE OF IONS IN SOLIDS," Book , Pergamon Press (U.S.A, U.K., Canada, Australia, Federal Republic of Germany), p. 109-110, 2, (February 8, 1985).	
	C	FERAIN, E. AND LEGRAS, R., "Track-etched membrane: dynamics of pore formation," Journal, Elsevier Science B.V. (North Holland), No. B84, p. 331-336, (February 8, 1994).	
	D	OKUYAMA, Y; HASHIMOTO, T.; KOGUCHI, T., "High Dose Ion Implantation into Photoresist," Journal, J. Electrochem. Soc. (Japan), Vol. 125 (No. 8), p. 1293-1298, (August 8, 1978).	
	E	VALIEV, K.A.; VELIKOV, L.V.; DUSHENKOV, S.D., "Pore formation in PMMA during x-ray exposure," Journal, Sov. Phys. Tech. Phys. (USSR), Vol. 32 (No. 7), p. 862-863, (February 8, 1988).	
	F	ORVEK, KEVI J.; HUFFMAN, CRAIG, "CARBONIZED LAYER FORMATION IN ION IMPLANTED PHOTORESIST MASKS," Journal, Elsevier Science Publishers BV (North Holland, Amsterdam), Vol. B (No. 7/8), p. 501-506, (February 8, 1985).	
	G	HICKS, C. et al., "Development and Clinical Assessment of an Artificial Cornea," Journal, Progress in Retinal and Eye Research, Elsevier Science Ltd. (Great Britain), Vol. 19 (No. 2), p 149-170 (2000).	
	H	TRAUTMAN, C., et al., "Etching threshold for ion tracks in polyimide," Journal, Nuclear Instruments and Methods in Physics Research B, Elsevier Science B.V. (North Holland, Amsterdam), Vol. B (No. 115), p. 429-433 (1996)	
	I	VIRK, H.S., et al., "Effects on insulators of swift-heavy-ion irradiation: ion-track technology," Journal, J. Phys. D: Appl. Phys., IOP Publishing Ltd. (UK), Vol. 31, p. 3139-3145, (1998).	
MDV	J	YASHAR, Alyson G., "Artificial iris device may reduce glare," Magazine, Ophthalmology Times, Advanstar Communications, Inc., (September 15, 2000)	

Examiner Signature

M. Vaughn

Date Considered

11/30/05

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